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Concluded

providing a test substrate having mutually separated connecting contact points for a probe of a probe card, having mutually separated further connecting contact points for a reference probe, and having conductor tracks each connecting one of the connecting contact points to a respective one of the further connecting contact points to define contact point pairs;

placing a probe of a probe card on a connecting contact point and placing a reference probe onto the further connecting contact point of a respective contact point pair; and

calibrating the test system, including the probe card, by using the reference probe as a reference point for a respective signal path and adjusting the signal path to obtain same propagation-times for all signals.
